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APPLICANTS

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**\*\* CONTINUING DATA \*\*\*\*\***

This application is a DIV of 10/057,711 01/24/2002 PAT 6,670,819  
 which is a DIV of 09/411,139 10/01/1999 PAT 6,657,450  
 which is a DIV of 09/267,990 03/12/1999 PAT 6,380,754  
 which is a DIV of 08/895,764 07/17/1997 PAT 6,127,195  
 which is a CON of 08/621,157 03/21/1996 ABN  
 which is a CON of 08/206,747 03/04/1994 PAT 5,523,697  
 which is a DIV of 08/116,394 09/03/1993 PAT 5,326,428

*checked re*

**\*\* FOREIGN APPLICATIONS \*\*\*\*\***

*None re*

IF REQUIRED, FOREIGN FILING LICENSE GRANTED  
**\*\* 10/28/2003**

Foreign Priority claimed <input type="checkbox"/> yes <input checked="" type="checkbox"/> no 35 USC 119 (a-d) conditions <input type="checkbox"/> yes <input checked="" type="checkbox"/> no <input type="checkbox"/> Met after met Verified and Acknowledged	<input type="checkbox"/> yes <input checked="" type="checkbox"/> no <input type="checkbox"/> yes <input checked="" type="checkbox"/> no <input type="checkbox"/> Met after met Examiner's Signature <i>[Signature]</i> Initials <i>[Initials]</i>	STATE OR COUNTRY ID	SHEETS DRAWING 10	TOTAL CLAIMS 11/28	INDEPENDENT CLAIMS 1/10
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ADDRESS  
 021567  
 WELLS ST. JOHN P.S.  
 601 W. FIRST AVENUE, SUITE 1300  
 SPOKANE, WA  
 99201

TITLE  
 Method and apparatus for testing semiconductor circuitry for operability and method of forming apparatus for testing semiconductor circuitry for operability

☐ All Fees

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